

# HiPerFET™ Power MOSFET

N-Channel Enhancement Mode  
 Avalanche Rated, High  $dv/dt$ , Low  $t_{rr}$

$$V_{DSS} = 300V$$

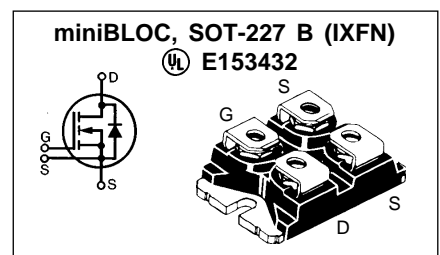
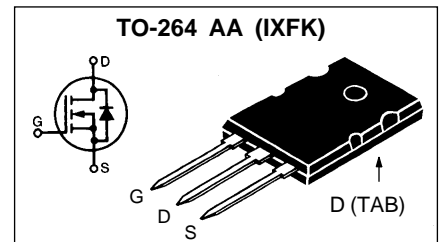
$$I_{D25} = 73A$$

$$R_{DS(on)} = 45m\Omega$$

$$t_{rr} \leq 200ns$$

Symbol	Test Conditions	Maximum Ratings		
		IXFK	IXFN	
$V_{DSS}$	$T_J = 25^\circ C$ to $150^\circ C$	300	300	V
$V_{DGR}$	$T_J = 25^\circ C$ to $150^\circ C$ ; $R_{GS} = 1 M\Omega$	300	300	V
$V_{GS}$	Continuous	$\pm 20$	$\pm 20$	V
$V_{GSM}$	Transient	$\pm 30$	$\pm 30$	V
$I_{D25}$	$T_C = 25^\circ C$	73	73	A
$I_{DM}$	$T_C = 25^\circ C$ , pulse width limited by $T_{JM}$	292	292	A
$I_{AR}$	$T_C = 25^\circ C$	40	40	A
$E_{AR}$	$T_C = 25^\circ C$	30	30	mJ
$dv/dt$	$I_S \leq I_{DM}$ , $di/dt \leq 100 A/\mu s$ , $V_{DD} \leq V_{DSS}$ , $T_J \leq 150^\circ C$ , $R_G = 2 \Omega$	5	5	V/ns
$P_D$	$T_C = 25^\circ C$	500	520	W
$T_J$		-55 ... +150		$^\circ C$
$T_{JM}$		150		$^\circ C$
$T_{stg}$		-55 ... +150		$^\circ C$
$T_L$	1.6 mm (0.063 in) from case for 10 s	300	-	$^\circ C$
$V_{ISOL}$	50/60 Hz, RMS $I_{ISOL} \leq 1 mA$	$t = 1 min$	-	2500 V~
		$t = 1 s$	-	3000 V~
$M_d$	Mounting torque	0.9/6	1.5/13	Nm/lb.in.
	Terminal connection torque	-	1.5/13	Nm/lb.in.
<b>Weight</b>		10	30	g

Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ C$ , unless otherwise specified)		
		Min.	Typ.	Max.
$V_{DSS}$	$V_{GS} = 0 V$ , $I_D = 1 mA$	300		V
$V_{GH(th)}$	$V_{DS} = V_{GS}$ , $I_D = 8 mA$	2		V
$I_{GSS}$	$V_{GS} = \pm 20 V_{DC}$ , $V_{DS} = 0$			$\pm 200 nA$
$I_{DSS}$	$V_{DS} = 0.8 V_{DSS}$ $V_{GS} = 0 V$	$T_J = 25^\circ C$		400 $\mu A$
		$T_J = 125^\circ C$		2 mA
$R_{DS(on)}$	$V_{GS} = 10 V$ , $I_D = 0.5 I_{D25}$ Pulse test, $t \leq 300 \mu s$ , duty cycle $d \leq 2 \%$		0.045	$\Omega$



G = Gate      D = Drain  
 S = Source      TAB = Drain  
 Either Source terminal at miniBLOC  
 can be used as Main or Kelvin Source

## Features

- International standard packages
- JEDEC TO-264 AA, epoxy meet UL 94 V-0, flammability classification
- miniBLOC with Aluminium nitride isolation
- Low  $R_{DS(on)}$  HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
- Fast intrinsic Rectifier

## Applications

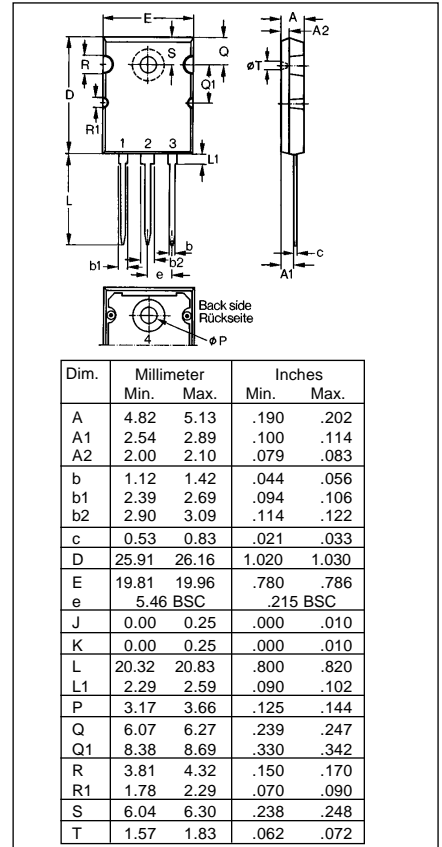
- DC-DC converters
- Synchronous rectification
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- Temperature and lighting controls
- Low voltage relays

## Advantages

- Easy to mount
- Space savings
- High power density

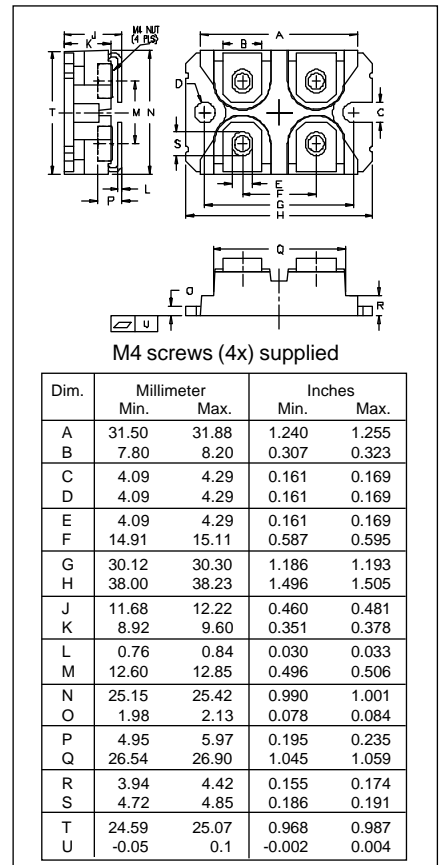
Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		Min.	Typ.	Max.
$g_{fs}$	$V_{DS} = 10\text{ V}; I_D = 0.5 I_{D25}$ , pulse test		50	S
$C_{iss}$	$V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1\text{ MHz}$		9000	pF
$C_{oss}$			1500	pF
$C_{rss}$			580	pF
$t_{d(on)}$	$V_{GS} = 10\text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$ $R_G = 1\ \Omega$ (External),		30	ns
$t_r$			80	ns
$t_{d(off)}$			100	ns
$t_f$			50	ns
$Q_{g(on)}$	$V_{GS} = 10\text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$		360	nC
$Q_{gs}$			60	nC
$Q_{gd}$			180	nC
$R_{thJC}$	TO-264 AA		0.25	K/W
$R_{thCK}$	TO-264 AA		0.15	K/W
$R_{thJC}$	miniBLOC, SOT-227 B		0.24	K/W
$R_{thCK}$	miniBLOC, SOT-227 B		0.05	K/W

**TO-264 AA Outline**



Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		Min.	Typ.	Max.
$I_S$	$V_{GS} = 0$			73 A
$I_{SM}$	Repetitive; pulse width limited by $T_{JM}$			292 A
$V_{SD}$	$I_F = I_S$ A, $V_{GS} = 0$ V, Pulse test, $t \leq 300\ \mu\text{s}$ , duty cycle $d \leq 2\%$			1.5 V
$t_{tr}$	$I_F = I_S$ , $-di/dt = 100\text{ A}/\mu\text{s}$ , $V_R = 100\text{ V}$		40	200 ns
$I_{RM}$				A

**miniBLOC, SOT-227 B**



IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETS and IGBTs are covered by one or more of the following U.S. patents:

4,835,592    4,881,106    5,017,508    5,049,961    5,187,117    5,486,715  
4,850,072    4,931,844    5,034,796    5,063,307    5,237,481    5,381,025

Fig.1. Output Characteristics

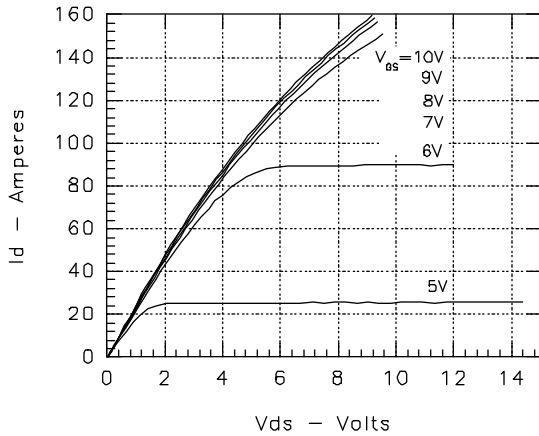


Fig. 2. Input Admittance

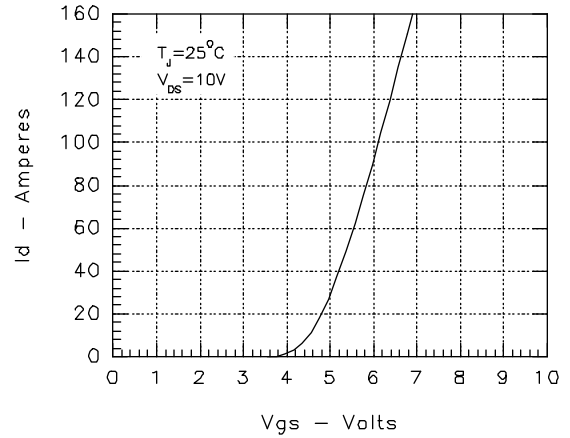


Fig. 3. Rds(on) vs. Drain Current

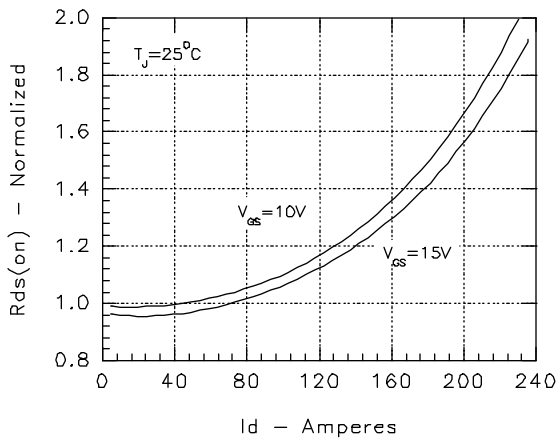


Fig. 4. Temperature Dependence of Drain to Source Resistance

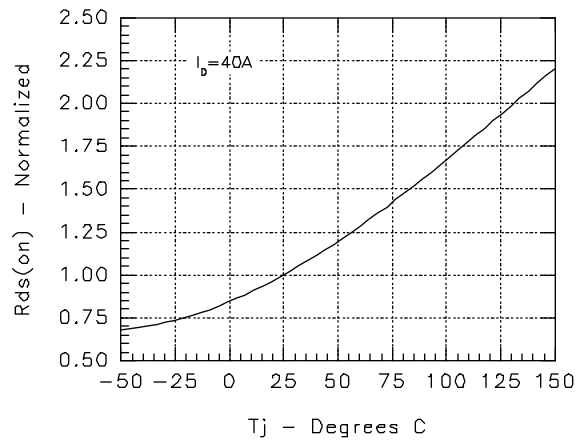


Fig. 5. Drain Current vs. Case Temperature

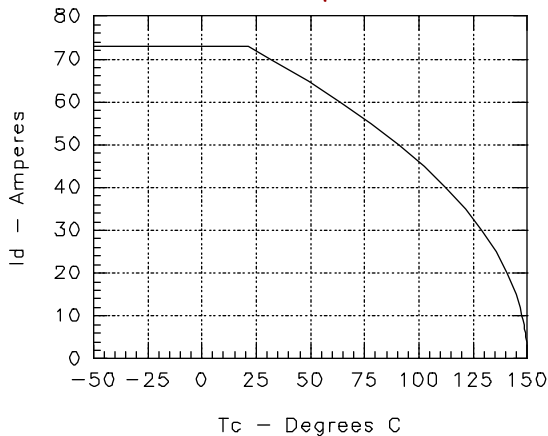
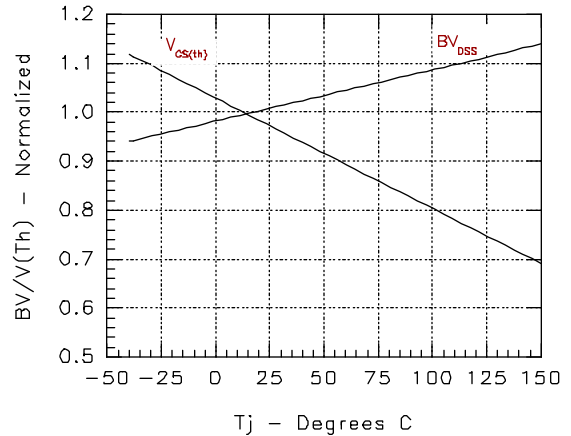
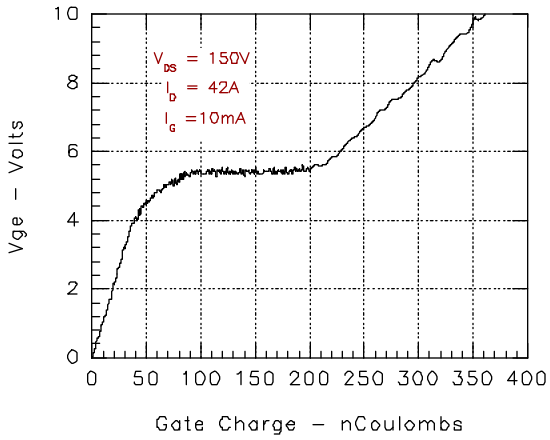


Fig. 6. Temperature Dependence of Breakdown Voltage and Threshold Voltage

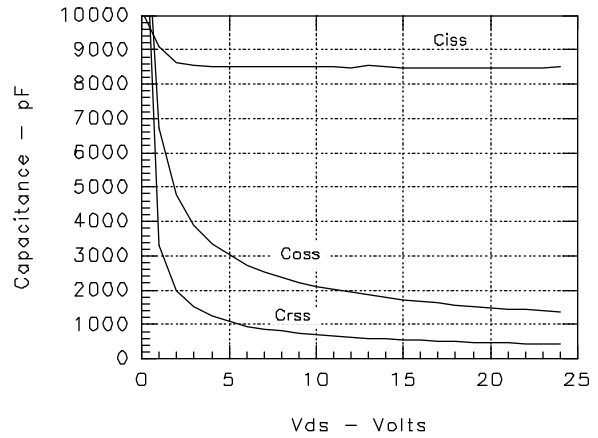


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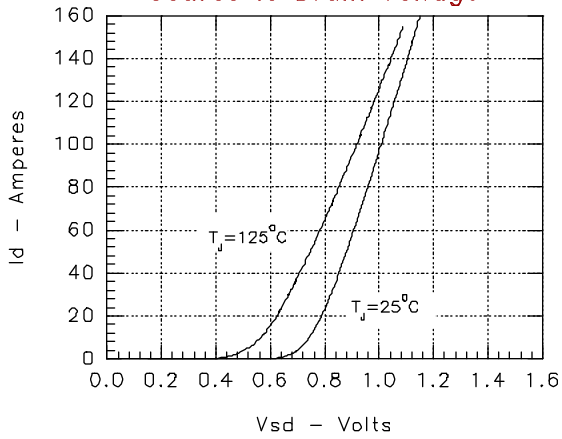
**Fig. 7. Gate Charge**



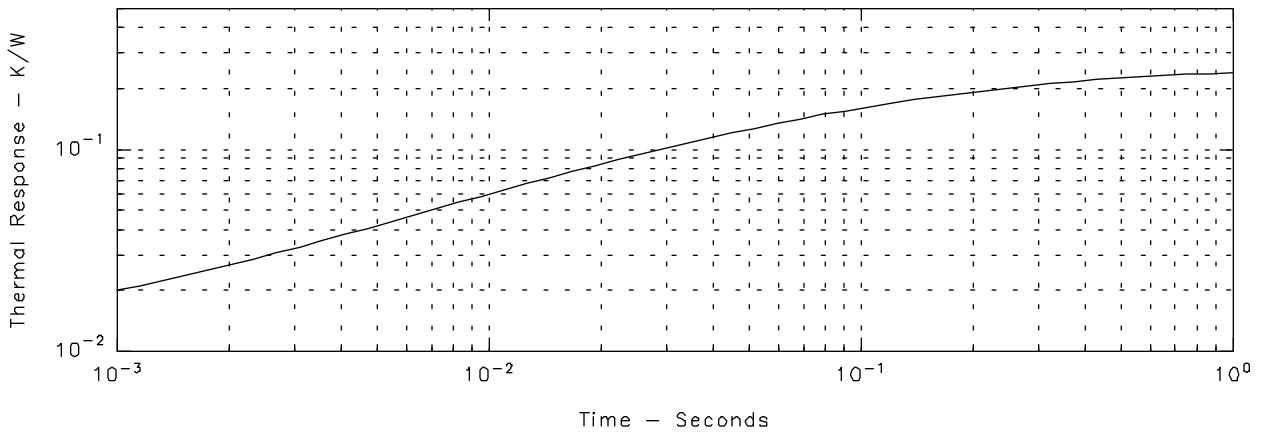
**Fig. 8. Capacitance Curves**



**Fig. 9. Source Current vs. Source to Drain Voltage**



**Fig. 10. Transient Thermal Impedance**



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